



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: TB1904-03 Product Affected: F2913NLGK F2913NLGK8 Date Effective: 6-Aug-2019	DATE: 6-May-2019	MEANS OF DISTINGUISHING CHANGED DEVICES: <input type="checkbox"/> Product Mark <input type="checkbox"/> Back Mark <input type="checkbox"/> Date Code <input checked="" type="checkbox"/> Other Traceability to the test location is maintained by IDT and available on request
Contact: IDT PCN DESK E-mail: pcndesk@idt.com	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Samples: Please contact your local sales representative for sample request.	

DESCRIPTION AND PURPOSE OF CHANGE:

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input checked="" type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input type="checkbox"/> Other	<p>This notification is to advise our customers that IDT is adding Sigurd, Taiwan as an alternate facility for Test process for the selective products that are presently tested in IDT Penang, Malaysia facility.</p> <p>Attachment I details the change.</p>
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RELIABILITY/QUALIFICATION SUMMARY:

There is no expected change to the product quality or reliability performance. Please refer to Attachment I for Electrical correlation data.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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ATTACHMENT I - PCN # : TB1904-03

PCN Type: Manufacturing Site - Alternate Test Location

Data Sheet Change: None

Detail Of Change:

This notification is to advise our customers that IDT is adding Sigurd, Taiwan as an alternate facility for Test process for the selective products that are presently tested in IDT Penang, Malaysia facility.

This change will allow IDT the flexibility to ship from either facilities and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Load boards are the same at the qualified facilities. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.



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Qualification Information and Qualification Data:

Electrical Test Correlation Results

Vehicle: F2913

Sample size: 10 good and 5 reject units; 10 loop test correlation

Description	Existing Test (IDT, Penang)	Alternate Test (Sigurd, Taiwan)
Tester Platform	J750	UltraFlex
Test Program	F2913_FT_rev0.4	F2913_UFlex_v1
Test Site	Dual Site	Octal Site
Test Temperature	Ambient	Ambient
Test Correlation Results	100%	100%
Number of Good Units	10 pcs	10 pcs
10 good units datalog correlation	Passed	Passed
Number of Loop Test	10	10
10 good units datalog correlation	Passed	Passed
Number of Reject Units	5 pcs	5 pcs
5 reject units datalog correlation	Passed	Passed